Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 293482US0PCT		SERIAL NO. 10/588,080				
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LIST OF REFERENCES CITED BY APPLICANT				Naoyoshi HATAKEYAMA, et al.					
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				January 10, 2007		1752			
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Examiner					Date Co	Date Considered			
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